STRATA

Strata 400S Dual Beam



- Dual beam system uses electron beam for imaging and gallium ions for imaging and precise micromachining
- High resolution imaging down to the nanometer level



Titanium oxide spheres mixed with diatom skeletons.

UConn seal ion milled into silicon.



Center for Advanced Microscopy and Materials Analysis

Thermo Fisher S C I E N T I F I C